

# **FDS6892AZ**

# **Dual N-Channel Logic Level PWM Optimized PowerTrench® MOSFET**

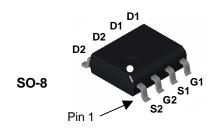
### **General Description**

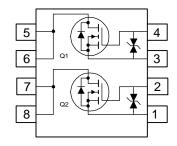
These N-Channel Logic Level MOSFETs are produced using Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimize the on-state resistance and yet maintain superior switching performance.

These devices are well suited for low voltage and battery powered applications where low in-line power loss and fast switching are required.

#### **Features**

- 7.5 A, 20 V.  $R_{DS(ON)} = 18 \ m\Omega \ @ \ V_{GS} = 4.5 \ V$   $R_{DS(ON)} = 24 \ m\Omega \ @ \ V_{GS} = 2.5 \ V$
- Low gate charge (12 nC typical)
- High performance trench technology for extremely low R<sub>DS(ON)</sub>
- · High power and current handling capability





### Absolute Maximum Ratings TA=25°C unless otherwise noted

Symbol	Parameter	Ratings	Units	
V <sub>DSS</sub>	Drain-Source Voltage	20	V	
V <sub>GSS</sub>	Gate-Source Voltage		± 12	V
I <sub>D</sub>	Drain Current - Continuous	(Note 1a)	7.5	Α
	- Pulsed		30	
P <sub>D</sub>	Power Dissipation for Dual Operation		2	W
	Power Dissipation for Single Operation	(Note 1a)	1.6	
		(Note 1b)	1	
		(Note 1c)	0.9	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperat	ture Range	-55 to +150	°C

### **Thermal Characteristics**

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	78	°C/W
R <sub>eJC</sub>	Thermal Resistance, Junction-to-Case	(Note 1)	40	°C/W

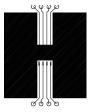
**Package Marking and Ordering Information** 

Device Marking	ce Marking Device		Tape width	Quantity	
FDS6892AZ	FDS6892AZ	13"	12mm	2500 units	

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	racteristics			I	I	l
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, \qquad I_{D} = 250  \mu\text{A}$	20			V
ΔBV <sub>DSS</sub> ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	$I_D$ = 250 $\mu$ A, Referenced to 25°C		14		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = 16 \text{ V},  V_{GS} = 0 \text{ V}$ $V_{DS} = 16 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55^{\circ}\text{C}$			1 10	μА
I <sub>GSSF</sub>	Gate-Body Leakage, Forward	$V_{GS} = 12 \text{ V},  V_{DS} = 0 \text{ V}$			10	μΑ
I <sub>GSSR</sub>	Gate-Body Leakage, Reverse	$V_{GS} = -12 \text{ V},  V_{DS} = 0 \text{ V}$			-10	μΑ
On Char	acteristics (Note 2)					
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	0.6	1.0	1.5	V
ΔV <sub>GS(th)</sub> ΔT <sub>J</sub>	Gate Threshold Voltage Temperature Coefficient	$I_D = 250 \mu\text{A}$ , Referenced to $25^{\circ}\text{C}$		-3		mV/°C
R <sub>DS(on)</sub>	Static Drain–Source On–Resistance	$\begin{array}{c ccccccccccccccccccccccccccccccccccc$		13 18 19	18 24 28	mΩ
I <sub>D(on)</sub>	On-State Drain Current	$V_{GS} = 4.5V$ , $V_{DS} = 5 V$	15			Α
<b>g</b> <sub>FS</sub>	Forward Transconductance	$V_{DS} = 5 \text{ V}, \qquad I_{D} = 7.5 \text{ A}$		36		S
Dynamic	Characteristics					
C <sub>iss</sub>	Input Capacitance	$V_{DS} = 10 \text{ V},  V_{GS} = 0 \text{ V},$		1286		pF
C <sub>oss</sub>	Output Capacitance	f = 1.0 MHz		305		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			161		pF
Switchir	ng Characteristics (Note 2)			•	•	
t <sub>d(on)</sub>	Turn-On Delay Time	$V_{DD} = 10 \text{ V},  I_D = 1 \text{ A},$		10	20	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{GS} = 4.5 \text{ V},  R_{GEN} = 6 \Omega$		14	25	ns
t <sub>d(off)</sub>	Turn-Off Delay Time			25	40	ns
t <sub>f</sub>	Turn-Off Fall Time			8	16	ns
Qg	Total Gate Charge	$V_{DS} = 10 \text{ V},  I_{D} = 7.5 \text{ A},$		12	17	nC
Q <sub>gs</sub>	Gate-Source Charge	V <sub>GS</sub> = 4.5 V		2.6		nC
$Q_{gd}$	Gate-Drain Charge	<u> </u>		3		nC
Drain-S	ource Diode Characteristics	and Maximum Ratings				
Is	Maximum Continuous Drain-Source				1.3	Α
V <sub>SD</sub>	Drain–Source Diode Forward Voltage	$V_{GS} = 0 \text{ V},  I_S = 1.3 \text{ A}  \text{(Note 2)}$		0.7	1.2	V

#### Notes:

 R<sub>8JA</sub> is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R<sub>8JC</sub> is guaranteed by design while R<sub>8CA</sub> is determined by the user's board design.



a) 78°C/W when mounted on a 0.5in<sup>2</sup> pad of 2 oz copper



b) 125°C/W when mounted on a 0.02 in² pad of 2 oz copper



c) 135°C/W when mounted on a minimum mounting pad.

Scale 1 : 1 on letter size paper

- 2. Pulse Test: Pulse Width < 300µs, Duty Cycle < 2.0%
- 3. The diode connected between the gate and source serves only as protection against ESD. No gate overvoltage rating is implied.

# **Typical Characteristics**

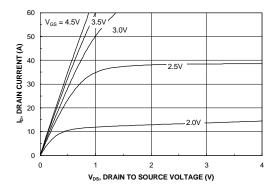


Figure 1. On-Region Characteristics.

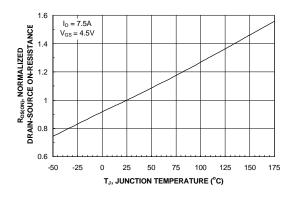


Figure 3. On-Resistance Variation with Temperature.

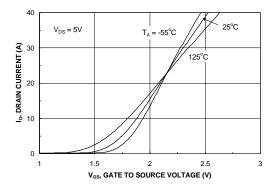


Figure 5. Transfer Characteristics.

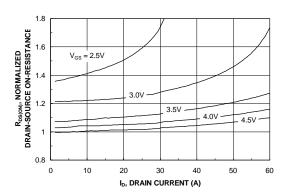


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

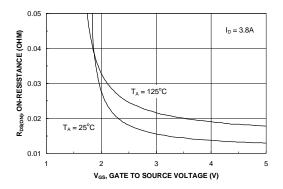


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

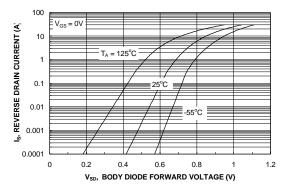
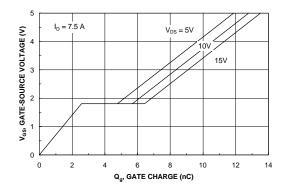


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

# **Typical Characteristics**



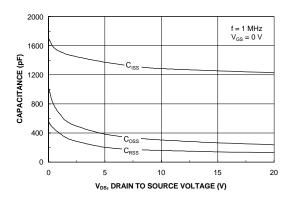
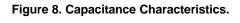
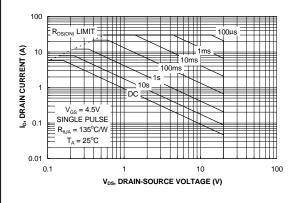


Figure 7. Gate Charge Characteristics.





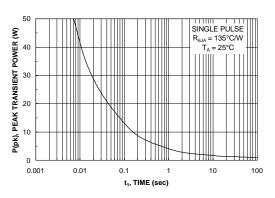


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

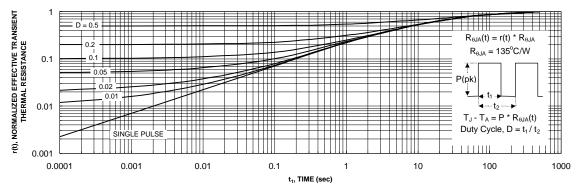
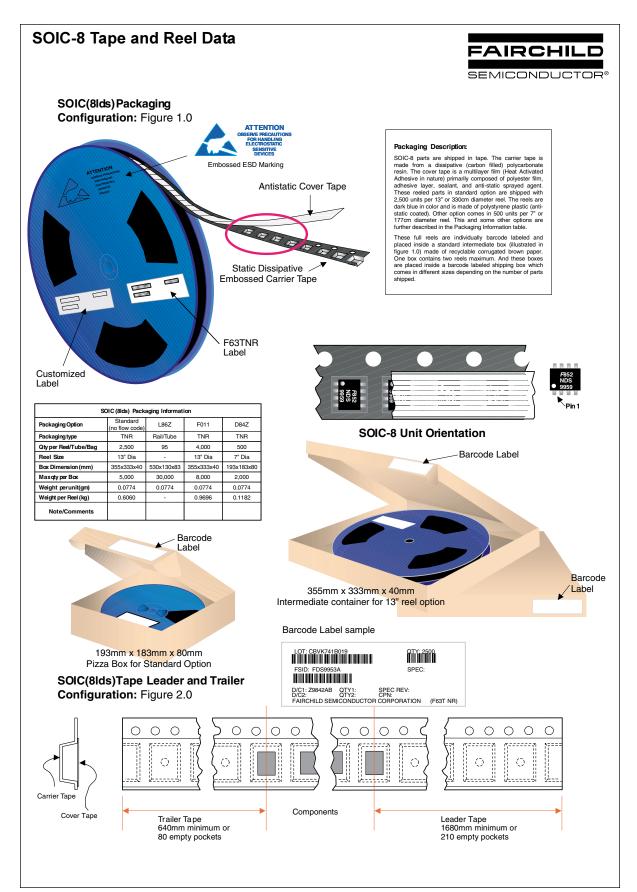


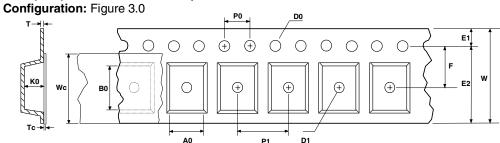
Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c. Transient thermal response will change depending on the circuit board design.





# SOIC(8lds) Embossed Carrier Tape



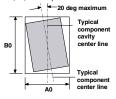


					Dim	ensions	are in mi	illimeter						
Pkg type	Α0	В0	w	D0	D1	E1	E2	F	P1	P0	КО	т	Wc	Тс
SOIC(8lds) (12mm)	5.30 +/-0.10	6.50 +/-0.10	12.0 +/-0.3	1.55 +/-0.05	1.60 +/-0.10	1.75 +/-0.10	10.25 min	5.50 +/-0.05	8.0 +/-0.1	4.0 +/-0.1	2.1 +/-0.10	0.450 +/- 0.150	9.2 +/-0.3	0.06 +/-0.02

Notes: A0, B0, and K0 dimensions are determined with respect to the EIA/Jedec RS-481 rotational and lateral movement requirements (see sketches A, B, and C).



Sketch A (Side or Front Sectional View)
Component Rotation



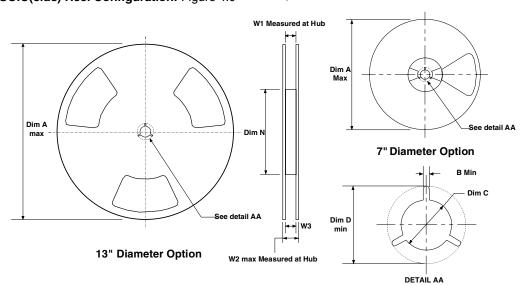
Sketch B (Top View)
Component Rotation



Sketch C (Top View)

Component lateral movement

### SOIC(8lds) Reel Configuration: Figure 4.0

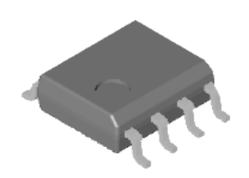


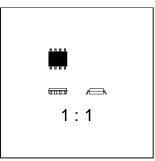
	Dimensions are in inches and millimeters								
Tape Size	Reel Option	Dim A	Dim B	Dim C	Dim D	Dim N	Dim W1	Dim W2	Dim W3 (LSL-USL)
12mm	7" Dia	7.00 177.8	0.059 1.5	512 +0.020/-0.008 13 +0.5/-0.2	0.795 20.2	2.165 55	0.488 +0.078/-0.000 12.4 +2/0	0.724 18.4	0.469 - 0.606 11.9 - 15.4
12mm	13" Dia	13.00 330	0.059 1.5	512 +0.020/-0.008 13 +0.5/-0.2	0.795 20.2	7.00 178	0.488 +0.078/-0.000 12.4 +2/0	0.724 18.4	0.469 - 0.606 11.9 - 15.4

# **SOIC-8 Package Dimensions**



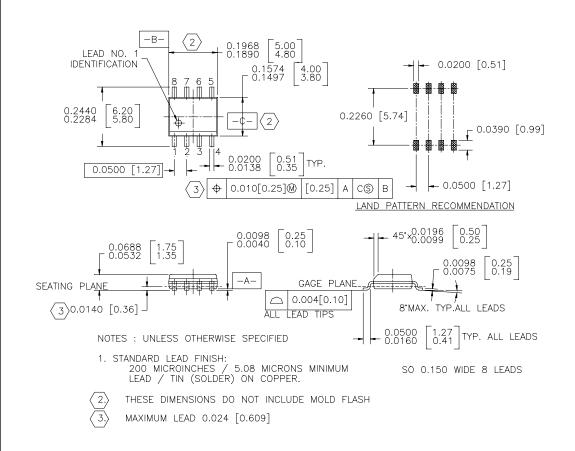
# SOIC-8 (FS PKG Code S1)





Scale 1:1 on letter size paper
Dimensions shown below are in:
inches [millimeters]

Part Weight per unit (gram): 0.0774



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No Identification Needed	Full Production	This datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
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